

Notice of References Cited	Application/Control No. 10/692,616		Applicant(s)/Patent Under Reexamination EYER, MARK KENNETH	
	Examiner Nam V. Nguyen		Art Unit 2612	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,229,433	05-2001	Rye et al.	340/310.12
	B	US-			
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	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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